2SC5505

Silicon NPN epitaxial planar type

For power amplification

Features

Collector current

Peak collector current

Junction temperature

Storage temperature

Collector power dissipation

- High-speed switching
- TO-220D built-in: Excellent package with withstand voltage 5 kV guaranteed

Symbol

V_{CBO}

V_{CEO}

V_{EBO}

 I_C

 I_{CP}

 P_C

Tį

T_{stg}

Rating

60

60

5

8

16

20

2.0

150

-55 to +150

Unit

v v

V

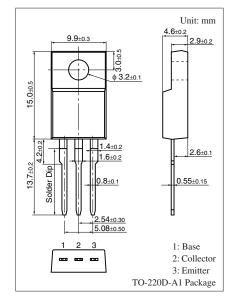
А

Α

W

°C

°C



Absolute Maximum Ratings $T_C = 25^{\circ}C$

Parameter

Collector-base voltage (Emitter open)

Collector-emitter voltage (Base open)

Emitter-base voltage (Collector open)

Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

 $T_a = 25^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	V _{CEO}	$I_{C} = 10 \text{ mA}, I_{B} = 0$	60			V
Collector-base cutoff current (Emitter open)	I _{CBO}	$V_{CB} = 60 \text{ V}, I_E = 0$			100	μΑ
Collector-emitter cutoff current (Base open)	I _{CEO}	$V_{CE} = 60 \text{ V}, I_B = 0$			100	μΑ
Forward current transfer ratio	h _{FE1}	$V_{CE} = 2 V, I_C = 1 A$	80		280	—
	h _{FE2}	$V_{CE} = 2 V, I_C = 5 A$	50			
Collector-emitter saturation voltage	V _{CE(sat)}	$I_{\rm C} = 5 \text{ A}, I_{\rm B} = 0.25 \text{ A}$			1.2	V
Base-emitter saturation voltage	V _{BE(sat)}	$I_{\rm C} = 5 \text{ A}, I_{\rm B} = 0.25 \text{ A}$			1.7	V
Turn-on time	t _{on}	$I_C = 4 A$		0.2	0.5	μs
Storage time	t _{stg}	$I_{B1} = 400 \text{ mA}, I_{B2} = -400 \text{ mA}$		0.5	1.0	μs
Fall time	t _f	$V_{CC} = 50 V$		0.10	0.15	μs

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

10

1 = 1 st = 10 ms t = 1 mst = 0.1 ms

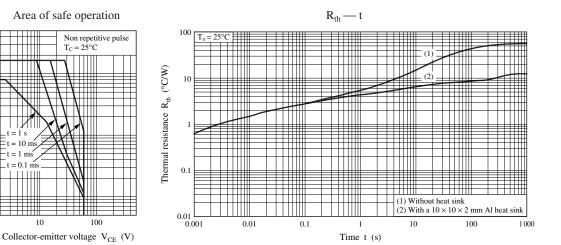
0.1

Collector current I_C (A)

10



100



2

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